

# SN74HSTL162822

## 14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

- Member of the Texas Instruments Widebus™ Family
- Inputs Meet JEDEC HSTL Standard JESD8-6
- All Outputs Have Equivalent 25-Ω Series Resistors
- Packaged in Plastic Thin Shrink Small-Outline Package

### description

This 14-bit to 28-bit D-type latch is designed for 3.15-V to 3.45-V  $V_{CC}$  operation. HSTL levels are expected on the inputs. LVTTL levels are driven on the Q outputs.

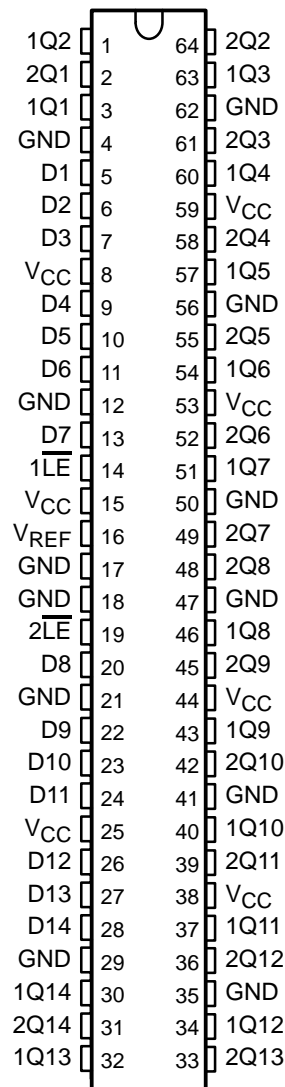
All outputs are designed to sink up to 12 mA and include 25-Ω series resistors to reduce overshoot and undershoot.

The SN74HSTL162822 is particularly suitable for driving an address bus to two banks of memory. Each bank of 14 outputs is controlled with its own latch-enable ( $\overline{LE}$ ) input.

Each of the 14 data (D) inputs is tied to the inputs of two D-type latches, which provide true data at the outputs. While  $\overline{LE}$  is low, the outputs (Q) of the corresponding 14 latches follow the D inputs. When  $\overline{LE}$  is taken high, the Q outputs are latched at the levels set up at the D inputs.

The SN74HSTL162822 is characterized for operation from -40°C to 90°C.

DGG PACKAGE  
(TOP VIEW)



FUNCTION TABLE

INPUTS		OUTPUT
$\overline{LE}$	D	Q
L	H	H
L	L	L
H	X	$Q_0^\dagger$

† Output level before the indicated steady-state input conditions were established



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.

Widebus is a trademark of Texas Instruments Incorporated.

PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.

**TEXAS  
INSTRUMENTS**

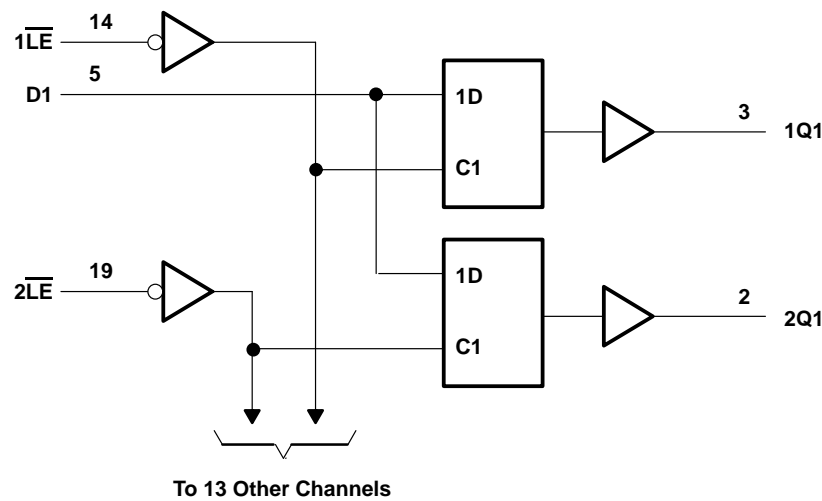
POST OFFICE BOX 655303 • DALLAS, TEXAS 75265

Copyright © 1997, Texas Instruments Incorporated

SN74HSTL162822
14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

logic diagram (positive logic)



absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Table with 2 columns: Parameter and Rating. Parameters include Supply voltage range, Input voltage range, Output voltage range, Input clamp current, Output clamp current, Continuous output current, Continuous current through each VCC or GND, Package thermal impedance, and Storage temperature range.

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied.

- NOTES: 1. The input and output negative-voltage ratings may be exceeded if the input and output clamp-current ratings are observed.
- 2. This current flows only when the output is in the high state and VO > VCC.
- 3. The package thermal impedance is calculated in accordance with EIA/JEDEC Std JESD51.

recommended operating conditions (see Note 4)

Table with 5 columns: Parameter, Description, MIN, NOM, MAX, UNIT. Parameters include VCC (Supply voltage), VREF (Reference voltage), VI (Input voltage), VIH (High-level input voltage), VIL (Low-level input voltage), IOH (High-level output current), IOL (Low-level output current), and TA (Operating free-air temperature).

NOTE 4: Unused inputs must be held high or low to prevent them from floating.

# SN74HSTL162822

## 14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

**electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)**

PARAMETER		TEST CONDITIONS	MIN	TYP <sup>†</sup>	MAX	UNIT
$V_{IK}$		$V_{CC} = 3.15\text{ V}$ , $I_I = -18\text{ mA}$			-1.2	V
$V_{OH}$		$V_{CC} = 3.15\text{ V}$ , $I_{OH} = -12\text{ mA}$	2.2			V
$V_{OL}$		$V_{CC} = 3.15\text{ V}$ , $I_{OL} = 12\text{ mA}$			0.8	V
$I_I$	Control inputs	$V_{CC} = 3.45\text{ V}$	$V_I = 0\text{ or }1.5\text{ V}$		5	$\mu\text{A}$
	Data inputs		$V_I = 0\text{ or }1.5\text{ V}$		5	
	$V_{REF}$		$V_{REF} = 0.68\text{ V or }0.9\text{ V}$		90	
$I_{CC}$		$V_{CC} = 3.45\text{ V}$ , $V_I = 0\text{ or }1.5\text{ V}$		50	100	mA
$C_i$	Control inputs	$V_{CC} = 0\text{ or }3.3\text{ V}$ , $V_I = 0\text{ or }3.3\text{ V}$		2		pF
	Data inputs	$V_{CC} = 0\text{ or }3.3\text{ V}$ , $V_I = 0\text{ or }3.3\text{ V}$		2		
$C_o$	Outputs	$V_{CC} = 0$ , $V_O = 0$		4		pF

<sup>†</sup> All typical values are at  $V_{CC} = 3.3\text{ V}$ ,  $T_A = 25^\circ\text{C}$ .

**timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted) (see Figure 1)**

		$V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$		UNIT
		MIN	MAX	
$t_w$	Pulse duration, $\overline{LE}$ low	3		ns
$t_{su}$	Setup time, D before $\overline{LE}\uparrow$	2		ns
$t_h$	Hold time, D after $\overline{LE}\uparrow$	1		ns

**switching characteristics over recommended operating free-air temperature range,  $V_{REF} = 0.75\text{ V}$**

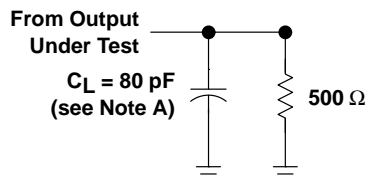
PARAMETER	FROM (INPUT)	TO (OUTPUT)	$V_{CC} = 3.3\text{ V} \pm 0.15\text{ V}$		UNIT
			MIN	MAX	
$t_{pd}$	D	Q	1.6	5	ns
	$\overline{LE}$		1.7	5.7	

# SN74HSTL162822

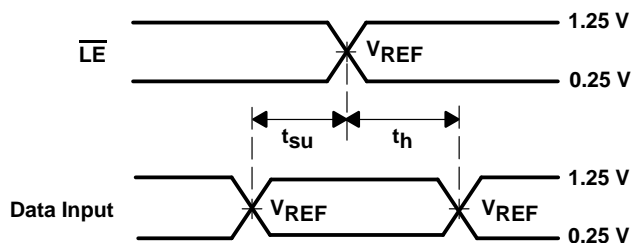
## 14-BIT TO 28-BIT HSTL-TO-LVTTL MEMORY ADDRESS LATCH

SCES091A – DECEMBER 1996 – REVISED APRIL 1997

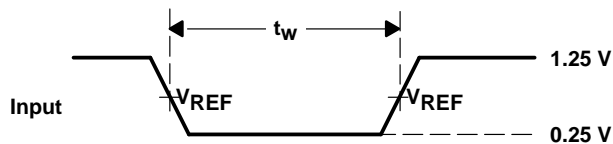
### PARAMETER MEASUREMENT INFORMATION



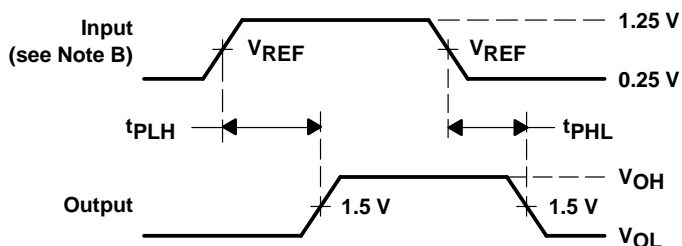
LOAD CIRCUIT



VOLTAGE WAVEFORMS  
SETUP AND HOLD TIMES



VOLTAGE WAVEFORMS  
PULSE DURATION



VOLTAGE WAVEFORMS  
PROPAGATION DELAY TIMES

- NOTES: A.  $C_L$  includes probe and jig capacitance.  
B. All input pulses are supplied by generators having the following characteristics:  $PRR \leq 10 \text{ MHz}$ ,  $Z_O = 50 \Omega$ ,  $t_r \leq 1 \text{ ns}$ ,  $t_f \leq 1 \text{ ns}$ .  
C. The outputs are measured one at a time with one transition per measurement.  
D.  $t_{PHL}$  and  $t_{PLH}$  are the same as  $t_{pd}$ .

Figure 1. Load Circuit and Voltage Waveforms

## **IMPORTANT NOTICE**

Texas Instruments (TI) reserves the right to make changes to its products or to discontinue any semiconductor product or service without notice, and advises its customers to obtain the latest version of relevant information to verify, before placing orders, that the information being relied on is current.

TI warrants performance of its semiconductor products and related software to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

Certain applications using semiconductor products may involve potential risks of death, personal injury, or severe property or environmental damage ("Critical Applications").

**TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, INTENDED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT APPLICATIONS, DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS.**

Inclusion of TI products in such applications is understood to be fully at the risk of the customer. Use of TI products in such applications requires the written approval of an appropriate TI officer. Questions concerning potential risk applications should be directed to TI through a local SC sales office.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards should be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance, customer product design, software performance, or infringement of patents or services described herein. Nor does TI warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used.